

May 2011

FDMS7606

Dual N-Channel PowerTrench[®] MOSFET Q1: 30 V, 12 A, 11.4 m Ω Q2: 30 V, 22 A, 11.6 m Ω

Features

Q1: N-Channel

- Max $r_{DS(on)}$ = 11.4 m Ω at V_{GS} = 10 V, I_D = 11.5 A
- Max $r_{DS(on)}$ = 15.7 m Ω at V_{GS} = 4.5 V, I_D = 10 A

Q2: N-Channel

- Max $r_{DS(on)}$ = 11.6 m Ω at V_{GS} = 10 V, I_D = 12 A
- Max $r_{DS(on)}$ = 17.2 m Ω at V_{GS} = 4.5 V, I_D = 9.5 A
- RoHS Compliant

General Description

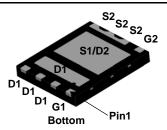
This device includes two specialized N-Channel MOSFETs in a dual MLP package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q1) and synchronous MOSFET (Q2) have been designed to provide optimal power efficiency.

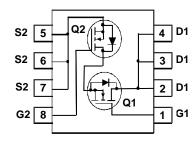
Applications

- Computing
- Communications
- General Purpose Point of Load
- Notebook Charger









Power 56

MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V _{DS}	Drain to Source Voltage		30	30	V
V _{GS}	Gate to Source Voltage	(Note 3)	±20	±20	V
	Drain Current -Continuous (Package limited)	T _C = 25 °C	12	22	
	-Continuous (Silicon limited)	T _C = 25 °C	41	39	_
I _D	-Continuous	T _A = 25 °C	11.5 ^{1a}	12 ^{1b}	A
	-Pulsed		50	60	
E _{AS}	Single Pulse Avalanche Energy	(Note 4)	25	33	mJ
D	Power Dissipation for Single Operation	T _A = 25°C	2.2 ^{1a}	2.5 ^{1b}	W
P_{D}	Power Dissipation for Single Operation	T _A = 25°C	1.0 ^{1c}	1.0 ^{1d}	VV
T _J , T _{STG}	Operating and Storage Junction Temperature Range -55 to +150				°C

Thermal Characteristics

Top

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	57 ^{1a}	50 ^{1b}	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	125 ^{1c}	120 ^{1d}	°C/W
$R_{\theta,IC}$	Thermal Resistance, Junction to Case	4.6	4.7	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS7606	FDMS7606	Power 56	13 "	12 mm	3000 units

Electrical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Off Chara	cteristics						
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	Q1 Q2	30 30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C	Q1 Q2		16 20		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V	Q1 Q2			1 1	μА
I _{GSS}	Gate to Source Leakage Curent	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	Q1 Q2			100 ±100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250 \mu A$	Q1 Q2	1.0 1.0	2.1 1.9	3.0 3.0	V	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C	Q1 Q2		-6 -5.5		mV/°C	
		$V_{GS} = 10 \text{ V}, I_D = 11.5 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 11.5 \text{ A}, T_J = 125^{\circ}\text{C}$	Q1		9.2 12.6 11.8	11.4 15.7 14.7		
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, \ I_D = 12 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \ I_D = 9.5 \text{ A}$ $V_{GS} = 10 \text{ V}, \ I_D = 12 \text{ A}, \ T_J = 125^{\circ}\text{C}$	Q2		9.7 12.8 12.3	11.6 17.2 15.4	mΩ	
g _{FS}	Forward Transconductance	$V_{DD} = 5 \text{ V}, I_{D} = 11.5 \text{ A}$ $V_{DD} = 5 \text{ V}, I_{D} = 12 \text{ A}$	Q1 Q2		53 47		S	

Dynamic Characteristics

C _{iss}	Input Capacitance	Q1: V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHZ	Q1 Q2		1050 947	1400 1260	pF
C _{oss}	Output Capacitance	Q2:	Q1 Q2		295 191	395 255	pF
C _{rss}	Reverse Transfer Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q1 Q2		32 131	50 200	pF
R _g	Gate Resistance		Q1 Q2	0.2 0.2	1.6 1.0	4.0 2.5	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time	Q1	Q1 Q2	7 6	14 12	ns	
t _r	Rise Time	V _{DD} = 15 V, I _D = 11	$V_{DD} = 15 \text{ V}, I_D = 11.5 \text{ A}, R_{GEN} = 6 \Omega$		3 3	10 10	ns
t _{d(off)}	Turn-Off Delay Time	Q2 Vpp = 15 V lp = 12	Q1 Q2	18 19	33 34	ns	
t _f	Fall Time	$V_{DD} = 15 \text{ V, } I_{D} = 12 \text{ A, } R_{GEN} = 6 \Omega$		Q1 Q2	3 3	10 10	ns
Q _{g(TOT)}	Total Gate Charge	V _{GS} = 0V to 10 V	Q1	Q1 Q2	16 19	22 27	nC
Q _{g(TOT)}	Total Gate Charge	$V_{GS} = 0V \text{ to } 5 \text{ V}$	$V_{DD} = 15 \text{ V},$ $I_{D} = 11.5 \text{ A}$	Q1 Q2	8 10	11 15	nC
Q _{gs}	Gate to Source Charge		Q2	Q1 Q2	3.2 2.6		nC
Q _{gd}	Gate to Drain "Miller" Charge		$V_{DD} = 15 \text{ V},$ $I_{D} = 12 \text{ A}$	Q1 Q2	2.0 4.2		nC

Electrical Characteristics T_J = 25°C unless otherwise noted

Parameter

Drain-S	Source Diode Characteristics						
		$V_{GS} = 0 \ V, I_{S} = 2 \ A$	(Note 2)	Q1	0.76	1.2	
V _{SD}	Source-Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 11.5 \text{ A}$	(Note 2)	Q1	0.87	1.2	V
	Source-Drain blode Forward voltage	$V_{GS} = 0 \text{ V, } I_{S} = 2 \text{ A}$	(Note 2)	Q2	0.75	1.2	v
		$V_{GS} = 0 V, I_{S} = 12 A$	(Note 2)	Q2	0.85	1.2	
+	Reverse Recovery Time	Q1		Q1	22	35	nc
чrr	Reverse Recovery Time	$I_F = 11.5 \text{ A}, \text{ di/dt} = 100 \text{ A/s}$		Q2	18	33	ns
0	Daverse Dassyery Charge	Q2		Q1	7	13	nC
Q_{rr}	Reverse Recovery Charge	$I_F = 12 A, di/dt = 100 A/s$		Q2	6	12	nc

Test Conditions

Symbol

 $R_{\theta JC}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. 57 °C/W when mounted on a 1 in² pad of 2 oz copper



b. 50 °C/W when mounted on a 1 in² pad of 2 oz copper

Type

Min

Тур

Max

Units



c. 125 °C/W when mounted on a minimum pad of 2 oz copper



d. 120 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3. As an N-ch device, the negative Vgs rating is for low duty cycle pulse occurrence only. No continuous rating is implied
- 4. Q1: E_{AS} of 25 mJ is based on starting T_J = 25 ^{o}C , L = 0.3 mH, I_{AS} = 13 A, V_{DD} = 27 V, V_{GS} = 10 V.
 - Q2: E_{AS} of 33 mJ is based on starting T_J = 25 ^{o}C , L = 0.3 mH, I_{AS} = 15 A, V_{DD} = 27 V, V_{GS} = 10 V.

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted

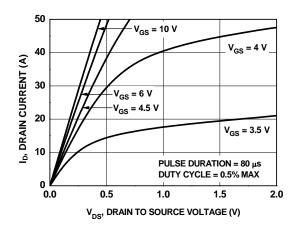


Figure 1. On Region Characteristics

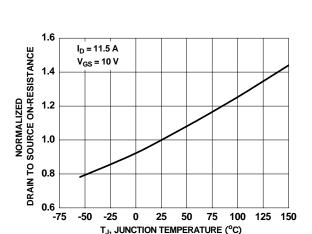


Figure 3. Normalized On Resistance vs Junction Temperature

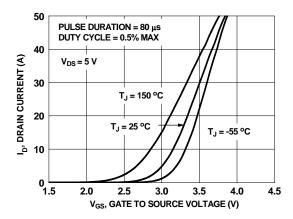


Figure 5. Transfer Characteristics

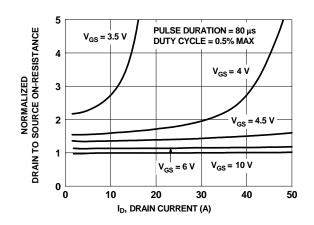


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

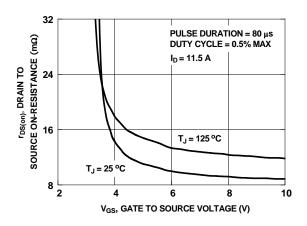


Figure 4. On-Resistance vs Gate to Source Voltage

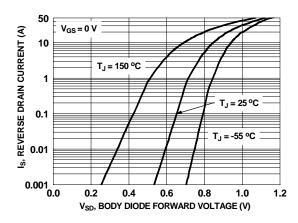


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted

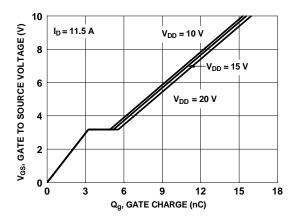


Figure 7. Gate Charge Characteristics

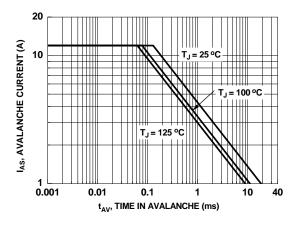


Figure 9. Unclamped Inductive Switching Capability

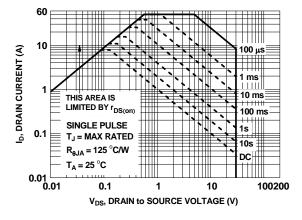


Figure 11. Forward Bias Safe Operating Area

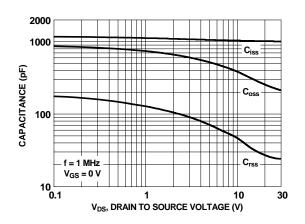


Figure 8. Capacitance vs Drain to Source Voltage

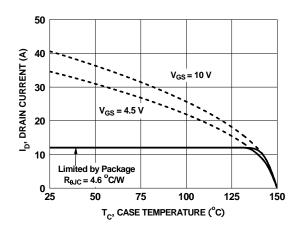


Figure 10. Maximum Continuous Drain Current vs Case Temperature

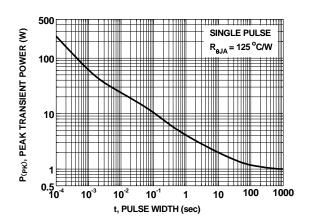


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q1 N-Channel) $T_J = 25$ °C unless otherwise noted

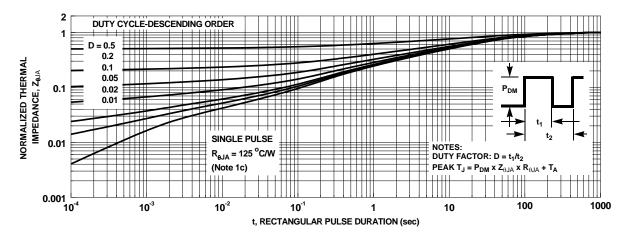


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (Q2 N-Channel) T_J = 25 °C unless otherwise noted

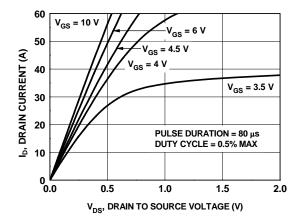


Figure 14. On-Region Characteristics

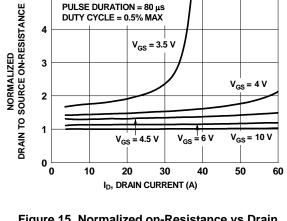


Figure 15. Normalized on-Resistance vs Drain Current and Gate Voltage

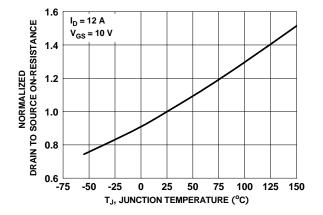


Figure 16. Normalized On-Resistance vs Junction Temperature

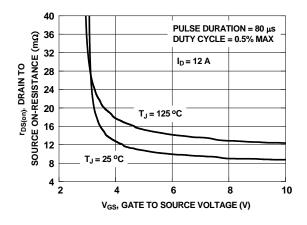


Figure 17. On-Resistance vs Gate to Source Voltage

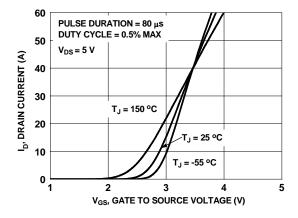


Figure 18. Transfer Characteristics

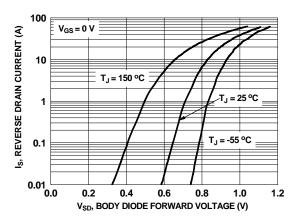


Figure 19. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q2 N-Channel) T_J = 25°C unless otherwise noted

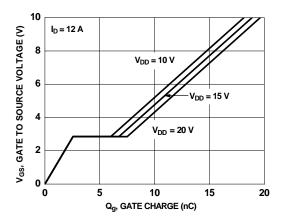


Figure 20. Gate Charge Characteristics

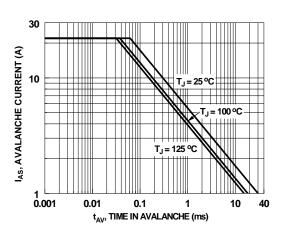


Figure 22. Unclamped Inductive Switching Capability

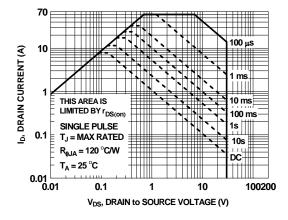


Figure 24. Forward Bias Safe Operating Area

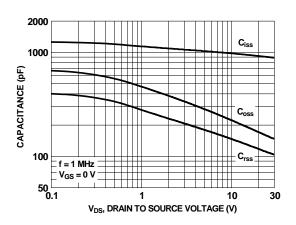


Figure 21. Capacitance vs Drain to Source Voltage

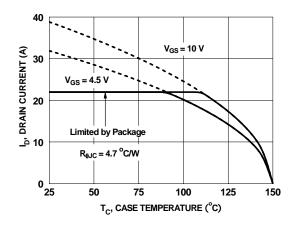


Figure 23. Maximum Continuous Drain Current vs Case Temperature

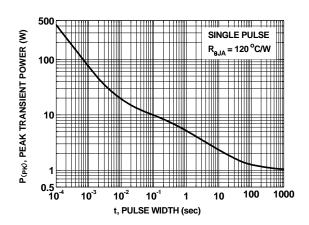


Figure 25. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q2 N-Channel) T_J = 25 °C unless otherwise noted

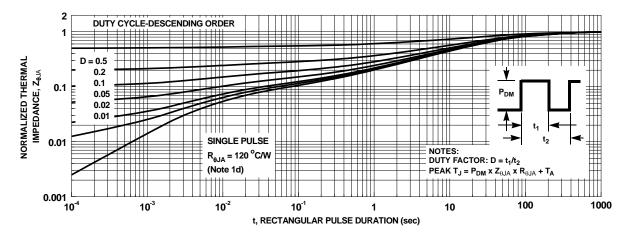
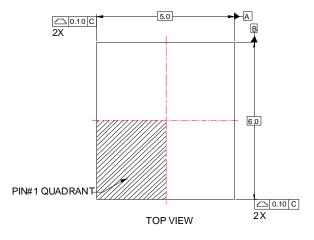
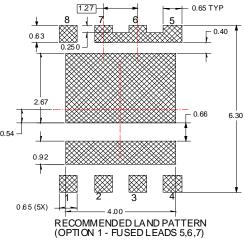
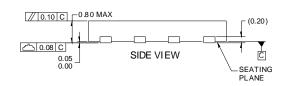


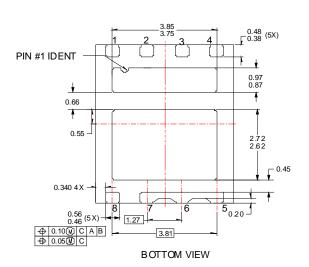
Figure 26. Junction-to-Ambient Transient Thermal Response Curve

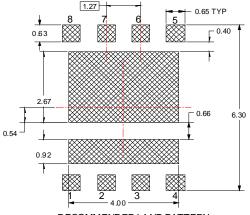
Dimensional Outline and Pad Layout











RECOMMENDED LAND PATTERN (OPTION 2 - ISOLATED LEADS)

- NOTES:
- A. DOES NOT FULLY CONFORM TO JEDEC REGISTRATION, MO-229.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- D. LAND PATTERN RECOMMENDATION IS BASED ON FSC DESIGN ONLY





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No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete Not In Production		Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

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